

Electronic supplementary information

Ultrahigh energy storage capacities in high-entropy relaxor ferroelectrics

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1. Material and methods

High-entropy $(1-x)(\text{Bi}_{0.375}\text{Na}_{0.3}\text{Sr}_{0.25}\text{K}_{0.075})\text{TiO}_3-x\text{Bi}(\text{Mg}_{0.5}\text{Sn}_{0.5})\text{O}_3$ ceramics (abbreviated as BNT-H100 x) with $x = 0.05, 0.10, 0.15,$ and 0.20 were synthesized through solid-reaction method with original materials including Bi_2O_3 (>99%), Na_2CO_3 (>99.8%), K_2CO_3 (>99%), TiO_2 (>98%), SrCO_3 (>99%), SnO_2 (>99.5%), and MgO (>98.5%) powders. The raw materials were dried at 110 °C for 12 h and then they were mixed by ball-milling in ethanol for 4 h. The mixed materials were then calcined at 880 °C for 2 h before they were ball-milled again for another 4 h. Powders obtained after drying were pressed into discs with a diameter of 9 mm and a thickness of 1 mm by isostatic pressure. These discs were sintered at 1180 °C for 120 min with a heating rate of 3 °C/min. For the VPP treatment, all powders were ball-milled again with 5% PVA solution to create a viscous substance. Then it was rolled into 0.6 mm thick flakes and cut into discs with a diameter of 10 mm. These discs produced by VPP was sintered at 1130 °C for 90 mins.

X-ray diffractometer (XRD; Panalytical, Cambridge, UK) was used to investigate phase structures of the samples. Sintered bulk ceramics were grinded into powders and then annealed at 500 °C for 4 h to relieve the internal stress. The TEM testing sample was fabricated by focused ion beam milling (FIB, Helios G4 CX, FEI, USA). A scanning electron microscope (SEM; quanta, FEG 250, FEI, Hillsboro, USA) was used to observe fresh surface of the sintered ceramics. The dark field images, the selected area electron diffraction (SAED) pattern, and high-resolution transmission electron microscope images were obtained by the spherical aberration corrected transmission electron microscope (AC-TEM, Titan Cubed Themis G2300, FEI, USA). The dielectric properties of ceramics were tested using a multi-frequency LCR

meter (E4980AL, Keysight, USA). The test temperature was 30–450 °C and heat up at a rate of 3 °C/min. The test frequencies were 0.3, 1, 10, 100, and 1000 kHz. A ferroelectric instrument (TF analyzer 2000E, aixACCT, Aachen, Germany) was used to measure the hysteresis loops and current curves. The test samples were grinded to 2 mm thick and then coated with gold electrode on both sides. The pulsed behavior was collected through a charge-discharge instrument (CFD-003, Gogo Instruments Technology, China).

Figures

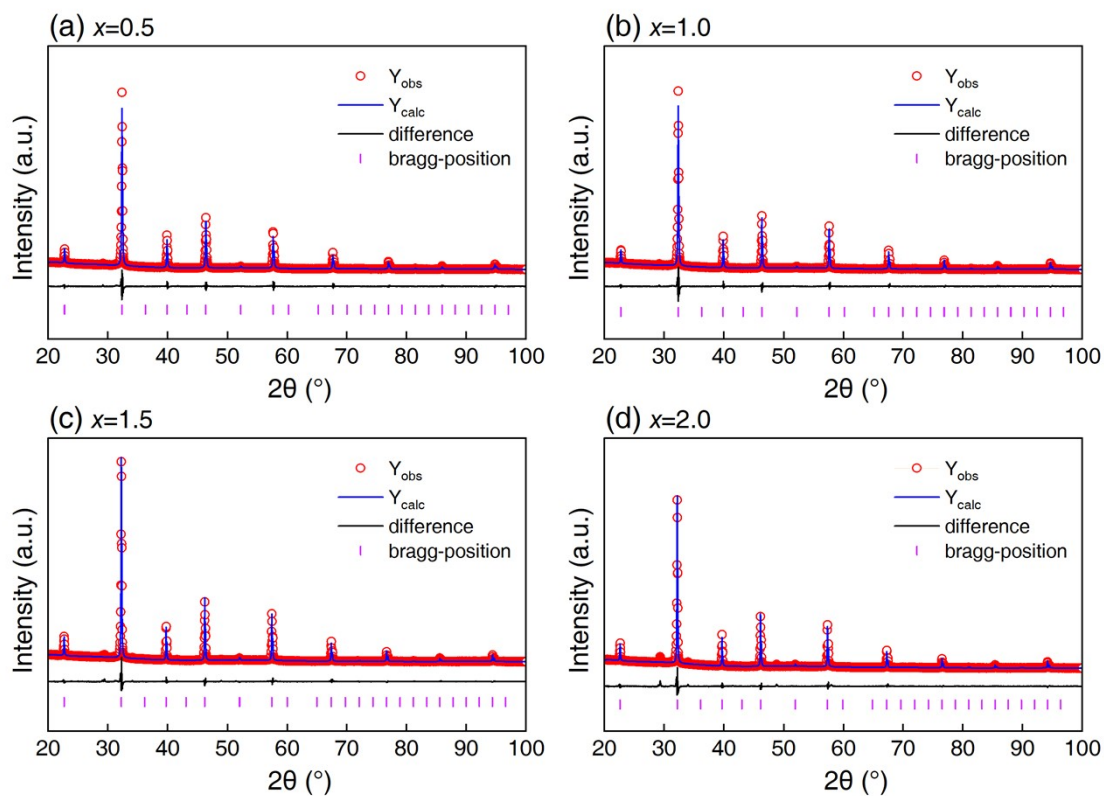


Fig. S1. Results of structure refinement for BNT-H100 x ceramics. (a) $x = 0.05$, (b) $x = 0.10$, (c) $x = 0.15$, and (d) $x = 0.20$.

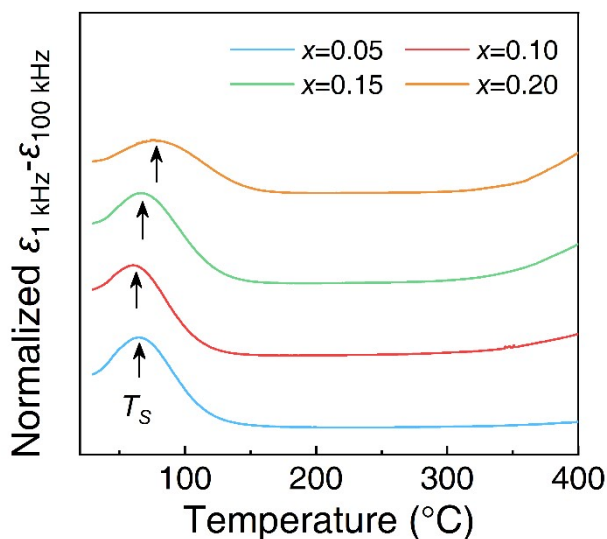


Fig. S2. Normalized $\varepsilon_{1 \text{ kHz}} - \varepsilon_{100 \text{ kHz}}$ as a function of temperature from RT to 400 °C. Here $\varepsilon_{1 \text{ kHz}}$ and $\varepsilon_{100 \text{ kHz}}$ were the ε_r measured at 1 kHz and 100 kHz, respectively. The characteristic temperature (T_s) is indicated by the vertical arrow.

Table S1Atomic configurational entropy S_{config} of BNT-H100 x ceramics.

x	0.05	0.10	0.15	0.20
S_{config}	1.49 <i>R</i>	1.63 <i>R</i>	1.73 <i>R</i>	1.82 <i>R</i>

Table S2Rietveld crystal refinement parameters of BNT-H100 x ceramics.

Chemical formula		$x = 0.5$	$x = 1.0$	$x = 1.5$	$x = 2.0$
Space group		<i>P4bm</i>	<i>P4bm</i>	<i>P4bm</i>	<i>P4bm</i>
Cell parameter (Å)	<i>a</i>	5.5456(9)	5.5494(3)	5.5595(6)	5.5672(9)
	<i>c</i>	3.9208(7)	3.9234(4)	3.9308(2)	3.9365(4)
Density (g/cm ³)		5.842(1)	6.002(3)	6.133(1)	6.273(9)
Volume (Å ³)		120.585	120.827	121.496	6.246
R-factors	R_{wp}	5.813	6.038	5.762	5.71
	χ^2	2.64	2.68	2.63	2.84
No. of profile points		6005	6005	6005	6005

Table S3

Comparison of ESP between various representative lead-free systems.

Composition	E (kV/cm)	W_{rec} (J/cm ³)	η (%)	Ref.
0.7374Na _{0.5} Bi _{0.5} TiO ₃ -0.2625BaSnO ₃	200	1.99	8.6	1
0.94(0.65Bi _{0.5} Na _{0.5} TiO ₃ -0.35Bi _{0.1} Sr _{0.85} TiO ₃)- 0.06(K _{0.5} Na _{0.5} NbO ₃)	180	2.65	84.6	2
0.55BNT-0.45(Bi _{0.2} Sr _{0.7} TiO ₃)	200	2.5	95	3
0.96(0.65BNT-0.35Sr _{0.85} Bi _{0.1} TiO ₃)-0.04NaNbO ₃	220	3.08	81.4	4
0.5BNT-0.5SrTiO ₃ -1.5 mol% CuO	230	2.2	72.39	5
0.9(0.7BNT-0.3SrTiO ₃)-0.1Bi(Nb _{0.5} Mg _{0.5})O ₃	240	3.46	78	6
0.6BNT-0.4Sr _{0.7} Sm _{0.2} TiO ₃	260	3.52	84.2	7
0.90(Na _{0.5} Bi _{0.5}) _{0.7} Sr _{0.3} TiO ₃ -0.10Bi(Ni _{0.5} Sn _{0.5})O ₃	270	4.18	83.64	8
0.6(Bi _{0.51} Na _{0.47})TiO ₃ -0.4Ba(Zr _{0.3} Ti _{0.7})O ₃	280	3.1	91	9
0.6(Ba _{0.7} Sr _{0.3})(Zr _{0.2} Ti _{0.8})O ₃ -0.4(Na _{0.5} Bi _{0.5})TiO ₃	289	3.72	94.3	10
(Na _{0.25} Bi _{0.25} Sr _{0.5})(Ti _{0.8} Sn _{0.2})O ₃	310	3.4	90	11
0.9(0.65 BNT-0.35Bi _{0.2} Sr _{0.7} TiO ₃)-0.1CaZrO ₃	330	2.9	80	12
0.85(0.55BNT-0.45Sr _{0.7} La _{0.2} TiO ₃)- 0.15Bi(Mg _{2/3} Nb _{1/3})O ₃	338	3.88	85	13
0.65(0.84BNT-0.16K _{0.5} Bi _{0.5} TiO ₃)-0.35(Bi _{0.2} Sr _{0.7} TiO ₃)	350	4.06	87.3	14
0.88BNT-0.12CaZr _{0.5} Ti _{0.5} O ₃	378.3	4.77	69	15
0.8(0.65BNT-0.35Bi _{0.2} Sr _{0.7} TiO ₃)-0.2BaSnO ₃	380	3.75	84.8	16
0.85(0.94BNT-0.06BaTiO ₃)-0.15BiMg _{2/3} Nb _{1/3} O ₃	420	6.3	80	17
(Na _{0.5} Bi _{0.5}) _{0.7} Sr _{0.3} TiO ₃ -Ba(Mg _{1/3} Nb _{2/3})O ₃	460	5.5	90.1	18
0.90(Bi _{0.5} Na _{0.5}) _{0.65} Sr _{0.35} TiO ₃ -0.10Bi(Mg _{0.5} Zr _{0.5})O ₃	522	8.46	85.9	19
0.75Bi _{0.58} Na _{0.42} TiO ₃ -0.25SrTiO ₃	535	5.63	94	20
0.7(0.85BNT-0.15NaNbO ₃)-0.3(Sr _{1.05} Bi _{0.3})ScO ₃	540	7.3	80	21
BSZT-BMN	552	5.92	81.7	22
(Bi _{0.5} (Na _{0.8} K _{0.2}) _{0.5}) _{0.96} Sr _{0.04} Ti _{0.99} Ta _{0.01} O ₃ -0.70BNT-	572	6.78	89.7	23

$0.30\text{SrNb}_{0.5}\text{Al}_{0.5}\text{O}_3$				
$0.96(0.8\text{NaNbO}_3-0.2\text{SrTiO}_3)-0.04\text{Bi}(\text{Zn}_{0.5}\text{Sn}_{0.5})\text{O}_3$	570	5.82	92.3	24
$0.78\text{NaNbO}_3-0.22\text{Bi}(\text{Mg}_{2/3}\text{Ta}_{1/3})\text{O}_3$	620	5.01	86.8	25
$\text{Bi}_{1.5}\text{Zn}_{0.75}\text{Mg}_{0.25}\text{Nb}_{0.75}\text{Ta}_{0.75}\text{O}_7$	650	2.72	91	26
$(\text{Ag}_{0.80}\text{Bi}_{0.04}\text{Sr}_{0.04})\text{NbO}_3$	720	7.9	75.5	27
$0.85(\text{Ba}_{0.8}\text{Sr}_{0.2})\text{TiO}_3-0.15\text{Bi}(\text{Mg}_{0.5}\text{Zr}_{0.5})\text{O}_3$	720	10.3	88	28
$(\text{Na}_{0.91}\text{Bi}_{0.09})(\text{Nb}_{0.94}\text{Mg}_{0.06})\text{O}_3$	783	10.9	83	29
$0.75[0.9\text{NN}-0.1\text{Bi}(\text{Mg}_{0.5}\text{Ta}_{0.5})\text{O}_3]-$ $0.25(\text{Bi}_{0.5}\text{Na}_{0.5})0.7\text{Sr}_{0.3}\text{TiO}_3$	800	8	90.4	30
$0.85\text{K}_{0.5}\text{Na}_{0.5}\text{NbO}_3-0.15\text{SrTiO}_3$	400	4.03	52	31
$0.8\text{K}_{0.5}\text{Na}_{0.5}\text{NbO}_3-0.2\text{SrTiO}_3$	400	3.67	72.1	
$0.92\text{NaNbO}_3-0.08\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$	480	5.57	71	32
$\text{BaTiO}_3-0.06\text{Bi}_{2/3}(\text{Mg}_{1/3}\text{Nb}_{2/3})\text{O}_3$	520	4.55	91	33
This work	610	11.29	90	

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